



30V N-CHANNEL ENHANCEMENT MODE MOSFET

Product Summary

V _{(BR)DSS}	R _{DS(ON)} max	I _D max T _A = 25°C
30V	12mΩ @ V _{GS} = 10V	10.3 A
30 V	16mΩ @ V _{GS} = 4.5V	9.3 A

Description

This MOSFET has been designed to minimize the on-state resistance (R_{DS(on)}) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

Applications

- Backlighting
- **Power Management Functions**
- **DC-DC Converters**

Features and Benefits

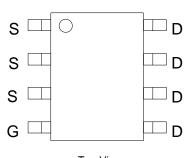
- Low On-Resistance
- Low Input Capacitance
- Fast Switching Speed
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)
- Qualified to AEC-Q101 standards for High Reliability

Mechanical Data

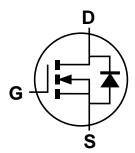
- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections Indicator: See diagram
- Terminals: Finish Matte Tin annealed over Copper leadframe. Solderable per MIL-STD-202, Method 208 @3
- Weight: 0.076 grams (approximate)







Top View Pin Configuration



Equivalent Circuit

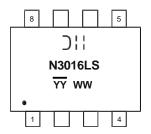
Ordering Information (Note 4)

Part Number	Case	Packaging
DMN3016LSS-13	SO-8	2500/Tape & Reel

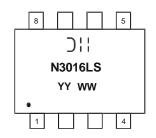
Notes:

- 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant.
- 2. See http://www.diodes.com/quality/lead_free.html for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain < 900ppm bromine, < 900ppm chlorine (< 1500ppm total Br + CI) and <1000ppm antimony compounds.
- 4. For packaging details, go to our website at http://www.diodes.com/products/packages.html.

Marking Information



Chengdu A/T Site



Shanghai A/T Site

);; = Manufacturer's Marking N3016LS = Product Type Marking Code YYWW = Date Code Marking YY or \overline{YY} = Year (ex: 14 = 2014)

WW = Week (01 - 53)

YY = Date Code Marking for SAT (Shanghai Assembly/ Test site) YY = Date Code Marking for CAT (Chengdu Assembly/ Test site)



Maximum Ratings (@T_A = +25°C, unless otherwise specified.)

Characteristic			Symbol	Value	Units
Drain-Source Voltage			V _{DSS}	30	V
Gate-Source Voltage			V _{GSS}	±20	V
Continuous Drain Current (Note 6) V _{GS} = 10V	Steady State	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I _D	10.3 8.3	А
	t<10s	$T_A = +25$ °C $T_A = +70$ °C	I _D	13.4 10.6	А
Continuous Drain Current (Note 6) // 4.5\/	Steady State	$T_A = +25$ °C $T_A = +70$ °C	I _D	9.3 7.3	А
Continuous Drain Current (Note 6) V _{GS} = 4.5V	t<10s	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I _D	12.0 9.5	А
Maximum Continuous Body Diode Forward Current (Note 6)			I _S	2.5	Α
Pulsed Drain Current (10µs pulse, duty cycle = 1%)			I _{DM}	80	Α
Avalanche Current (Note 7) L = 0.1mH			I _{AS}	22	Α
Avalanche Energy (Note 7) L = 0.1mH			Eas	25	mJ

Thermal Characteristics (@TA = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Units	
Total Power Dissipation (Note 5)	P_D	1.5	W	
Thermal Resistance, Junction to Ambient (Note 5)	Steady State	J	82	°C/W
Thermal Resistance, Junction to Ambient (Note 5)	t<10s	$R_{\theta JA}$	48	°C/W
Total Power Dissipation (Note 6)		P_{D}	2.0	W
Thermal Resistance, Junction to Ambient (Note 6)	Steady State	5	60	°C/W
Thermal Resistance, Junction to Ambient (Note 6)	t<10s	$R_{\theta JA}$	37	°C/W
Thermal Resistance, Junction to Case	$R_{ heta JC}$	6.4	°C/W	
Operating and Storage Temperature Range		T _J , T _{STG}	-55 to 150	°C

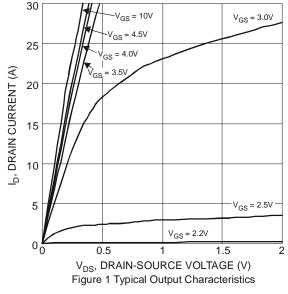
Electrical Characteristics (@T_A = +25°C, unless otherwise specified.)

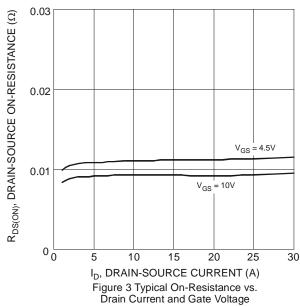
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 8)							
Drain-Source Breakdown Voltage	BV _{DSS}	30	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$	
Zero Gate Voltage Drain Current	I _{DSS}	_	_	1	μΑ	$V_{DS} = 30V, V_{GS} = 0V$	
Gate-Source Leakage	I _{GSS}	_	_	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 8)	•						
Gate Threshold Voltage	V _{GS(th)}	1.3	_	2.5	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	
Static Drain-Source On-Resistance		_	8	12	0	$V_{GS} = 10V, I_D = 12A$	
Static Drain-Source On-Resistance	R _{DS(ON)}	_	12	16	mΩ	$V_{GS} = 4.5V, I_D = 10A$	
Diode Forward Voltage	V _{SD}	_	0.7	1.0	V	$V_{GS} = 0V, I_{S} = 1A$	
DYNAMIC CHARACTERISTICS (Note 9)						•	
Input Capacitance	C _{iss}	_	1415	_		V _{DS} = 15V, V _{GS} = 0V, f = 1.0MHz	
Output Capacitance	Coss	_	119	_	pF		
Reverse Transfer Capacitance	C _{rss}	_	82	_			
Gate resistance	Rg	_	2.6	3.2	Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1.0MHz$	
Total Gate Charge (V _{GS} = 4.5V)	Qg	_	11.3	_		V _{DS} = 15V, I _D = 12A	
Total Gate Charge (V _{GS} = 10V)	Qq	_	25.1	_	nC		
Gate-Source Charge	Q _{gs}	_	3.5	_	IIC		
Gate-Drain Charge	Q _{gd}	_	3.6	_			
Turn-On Delay Time	t _{D(on)}	_	4.8	_		$V_{DD} = 15V, V_{GS} = 10V,$ $R_{L} = 1.25\Omega, R_{G} = 3\Omega,$	
Turn-On Rise Time	t _r	_	16.5				
Turn-Off Delay Time	t _{D(off)}	_	26.1	_	ns		
Turn-Off Fall Time	t _f		5.6	_	1		
Reverse Recovery Time	T _{rr}	_	8.5	_	ns	1 101 11/1 5001/	
Reverse Recovery Charge	Qrr	_	7.0	_	nC	$I_F = 12A$, di/dt = 500A/ μ s	

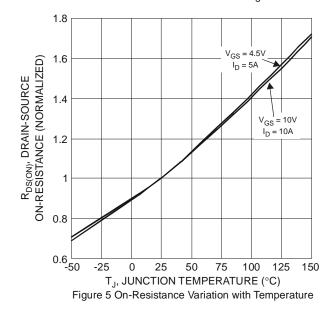
Notes:

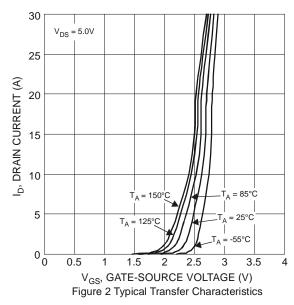
- 5. Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout.
- 6. Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.
- 7. UIS in production with L = 0.1mH, starting $T_A = +25$ °C.
- 8. Short duration pulse test used to minimize self-heating effect.
- 9. Guaranteed by design. Not subject to product testing.

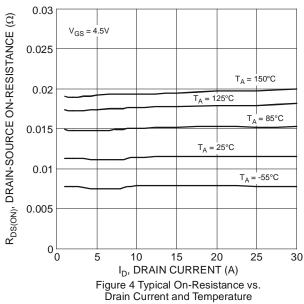


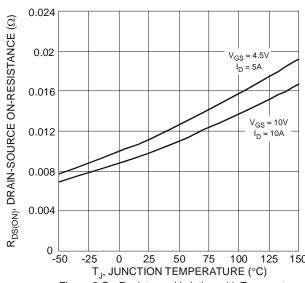














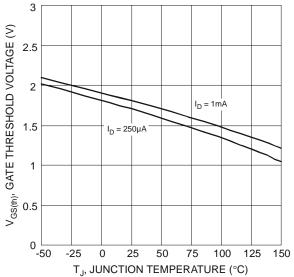


Figure 7 Gate Threshold Variation vs. Ambient Temperature

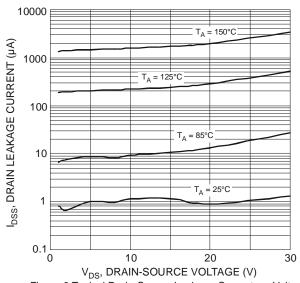
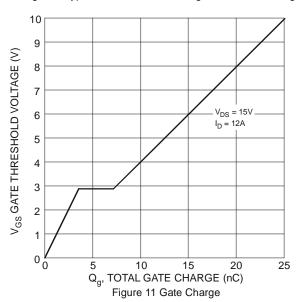
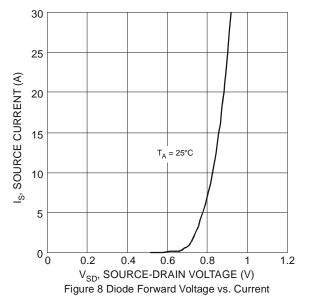
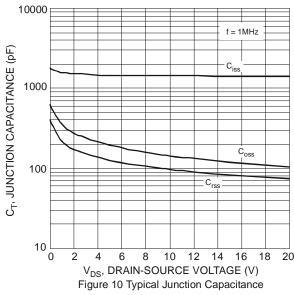


Figure 9 Typical Drain-Source Leakage Current vs. Voltage







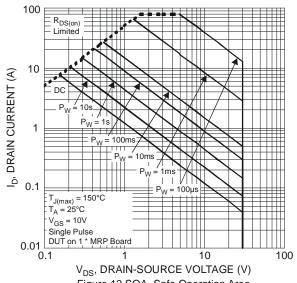
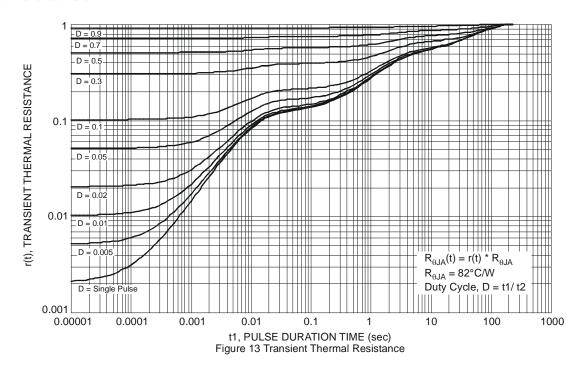


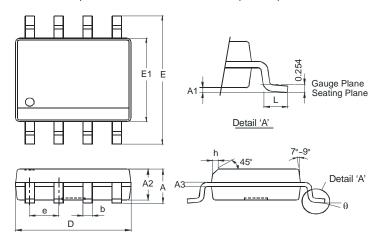
Figure 12 SOA, Safe Operation Area





Package Outline Dimensions

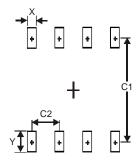
Please see AP02002 at http://www.diodes.com/datasheets/ap02002.pdf for the latest version.



SO-8					
Dim	Min	Max			
Α	-	1.75			
A 1	0.10	0.20			
A2	1.30	1.50			
А3	0.15	0.25			
b	0.3	0.5			
D	4.85	4.95			
Е	5.90	6.10			
E1	3.85 3.95				
е	1.27 Typ				
h	-	0.35			
L	0.62	0.82			
θ	0°	8°			
All Dimensions in mm					

Suggested Pad Layout

Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.



Dimensions	Value (in mm)
Х	0.60
Υ	1.55
C1	5.4
C2	1.27



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